

<b>Search Notes</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10591824	CHAN ET AL.
Examiner	Art Unit	
SUCHIRA PANDE	1637	

### SEARCHED

Class	Subclass	Date	Examiner

### SEARCH NOTES

Search Notes	Date	Examiner
Google search	June 2009	SP
PALM Inventor name search	July 2009	SP
East Search	July 2009	SP
Pubmed search	July 2009	SP
SEPs Gary Benzion, Peter Paras and Chris Low were consulted re "subject of chinese decent" phrase in claims. Use of this phrase makes this a SAW's case. It was decided that 112 2nd should be done as we do not know how much chinese does one have to be to qualify and how to determine that requisite percentage?	July 2009	SP

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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